

FOD819 Series

FOD819 4-Pin DIP High Speed Phototransistor Optocouplers

Description

The FOD819 consists of a gallium arsenide (GaAs) infra-red emitting diode, driving a high speed photo detector with integrated base-to-emitter resistor, R_{BE} , in a 4-pin dual-in-line package. It is designed to be an improved replacement to the popular FOD817 Series when higher speed performance is required in isolated data signal transmission.

Features

- High Speed Performance ~ 30 kHz
- Current Transfer Ratio: 100% to 600%
- Minimum BV_{CEO} of 80 V Guaranteed
- Safety and Regulatory Approvals:
 - UL1577, 5,000 VAC_{RMS} for 1 Minute
 - DIN EN/IEC60747-5-5, 850 V Peak Working Insulation Voltage

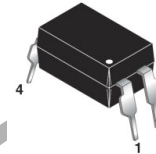
Typical Applications

- Digital Logic Inputs
- Microprocessor Inputs
- Power Supply Monitor
- Twisted Pair Line Receiver
- Telephone Line Receiver



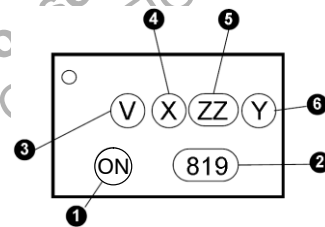
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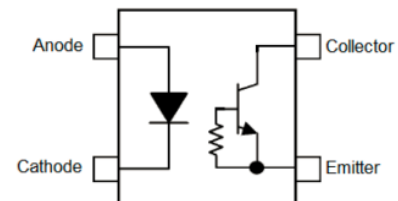
DIP 4 PINS

MARKING DIAGRAM



- 1. ON = Company Logo
- 2. 819 = Device Number
- 3. V = DIN EN/IEC60747-5-5 Option
- 4. X = One-Digit Year Code
- 5. ZZ = Digit Work Week
- 6. Y = Assembly Package Code

PIN CONNECTIONS



ORDERING INFORMATION

See detailed ordering and shipping information on page 7 of this data sheet.

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Safety and Insulation Ratings

As per DIN EN/IEC 60747-5-5, this optocoupler is suitable for “safe electrical insulation” only within the safety limit data. Compliance with the safety ratings shall be ensured by means of protective circuits.

Table 1. SAFETY AND INSULATION RATINGS

Parameter		Characteristics
Installation Classifications per DIN VDE 0110/1.89 Table 1, For Rated Mains Voltage	< 150 V _{RMS}	I-IV
	< 300 V _{RMS}	I-III
Climatic Classification		55/115/21
Pollution Degree (DIN VDE 0110/1.89)		2
Comparative Tracking Index		175

Table 2.

Symbol	Parameter	Value	Unit
V _{PR}	Input-to-Output Test Voltage, Method A, V _{IORM} × 1.6 = V _{PR} , Type and Sample Test with t _m = 10 s, Partial Discharge < 5 pC	1360	V _{peak}
	Input-to-Output Test Voltage, Method B, V _{IORM} × 1.875 = V _{PR} , 100% Production Test with t _m = 1 s, Partial Discharge < 5 pC	1594	V _{peak}
V _{IORM}	Maximum Working Insulation Voltage	850	V _{peak}
V _{IOTM}	Highest Allowable Over-Voltage	8000	V _{peak}
	External Creepage	≥ 7	mm
	External Clearance	≥ 7	mm
	External Clearance (for Option W, 0.4" Lead Spacing)	≥ 10	mm
DTI	Distance Through Insulation (Insulation Thickness)	≥ 0.4	mm
T _s	Case Temperature (Note 1)	175	°C
I _{S,INPUT}	Input Current (Note 1)	400	mA
P _{S,OUTPUT}	Output Power (Note 1)	700	mW
R _{IO}	Insulation Resistance at T _s , V _{IO} = 500 V (Note 1)	> 10 ¹¹	Ω

1. Safety limit values – maximum values allowed in the event of a failure.

Table 3. ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
TOTAL PACKAGE			
T _{STG}	Storage Temperature	-55 to +125	°C
T _{OPR}	Operating Temperature	-55 to +110	°C
T _J	Junction Temperature	-55 to +125	°C
T _{SOL}	Lead Solder Temperature	260 for 10 seconds	°C
θ _{JC}	Junction-to-Case Thermal Resistance	210	°C/W
P _{TOT}	Total Device Power Dissipation	200	mW
EMITTER			
I _F	Continuous Forward Current	50	mA
V _R	Reverse Voltage	6	V
P _D	Power Dissipation	70	mW
	Derate Above 100°C	1.7	mW/°C

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Table 3. ABSOLUTE MAXIMUM RATINGS (continued)

Symbol	Parameter	Value	Unit
DETECTOR			
V_{CEO}	Collector–Emitter Voltage	80	V
V_{ECO}	Emitter–Collector Voltage	2	V
I_C	Continuous Collector Current	30	mA
P_C	Collector Power Dissipation	150	mW
	Derate Above 90°C	2.9	mW/°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

Electrical Characteristics

Table 4. INDIVIDUAL COMPONENT CHARACTERISTICS ($T_A = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
EMITTER						
V_F	Forward Voltage	$I_F = 1.5\text{ mA}$		1.2	1.4	V
I_R	Reverse Current	$V_R = 4.0\text{ V}$			10	μA
C_t	Terminal Capacitance	$V = 0, f = 1\text{ kHz}$		30		pF
DETECTOR						
I_{CEO}	Collector Dark Current	$V_{CE} = 40\text{ V}, I_F = 0$			100	nA
BV_{CEO}	Collector–Emitter Breakdown Voltage	$I_C = 0.1\text{ mA}, I_F = 0$	80	150		V
BV_{ECO}	Emitter–Collector Breakdown Voltage	$I_E = 0.1\text{ mA}, I_F = 0$	2	7		V

DC TRANSFER CHARACTERISTICS

CTR	Current Transfer Ratio (Note 2)	$I_F = 1.5\text{ mA}, V_{CE} = 5\text{ V}$	100		600	%
$V_{CE(SAT)}$	Saturation Voltage	$I_F = 1.5\text{ mA}, I_C = 0.2\text{ mA}$			0.3	V
$I_{C(OFF)}$	OFF–state collector current	$V_F = 0.7\text{ V}, V_{CE} = 40\text{ V}$			10	μA

AC TRANSFER CHARACTERISTICS

t_R	Rise Time (Saturated)	$I_F = 1.5\text{ mA}, V_{CC} = 5\text{ V}, R_L = 10\text{ k}\Omega$ (Note 3)		12		μs
t_F	Fall Time (Saturated)			20		μs
t_{PHL}	Propagation Delay Time High–to–Low	$I_F = 1.5\text{ mA}, V_{CC} = 5\text{ V}, R_L = 10\text{ k}\Omega$ (Note 3)		9	30	μs
t_{PLH}	Propagation Delay Time Low–to–High			18	30	μs

- Current Transfer Ratio (CTR) = $I_C / I_F \times 100\%$.
- Refer to test circuit setup.

Table 5. ISOLATION CHARACTERISTICS ($T_A = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
V_{ISO}	Input–Output Isolation Voltage (Note 4)	$f = 60\text{ Hz}, t = 1\text{ minutes}, I_{I-O} \leq 2\text{ }\mu\text{A}$	5000			$V_{AC(RMS)}$
R_{ISO}	Isolation Resistance	$V_{I-O} = 500\text{ V}_{DC}$		1×10^{11}		Ω
C_{ISO}	Isolation Capacitance	$V_{I-O} = 0, f = 1\text{ MHz}$		0.6	1.0	pf

- For this test, Pins 1 and 2 are common, and Pins 3 and 4 are common.

Typical Performance Curves

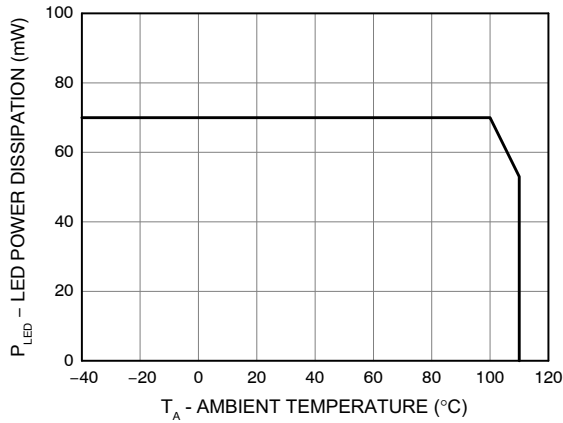


Figure 1. LED Power Dissipation vs. Ambient Temperature

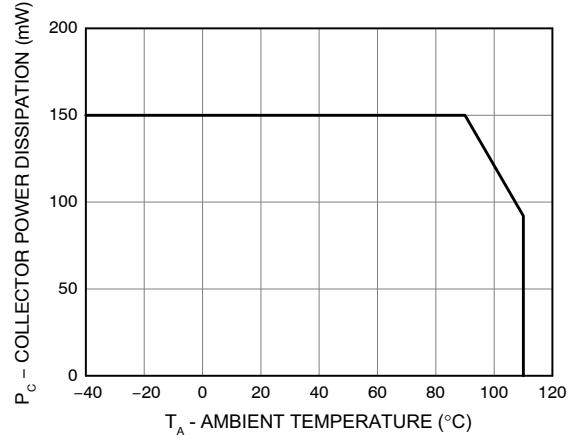


Figure 2. Collector Power Dissipation vs. Ambient Temperature

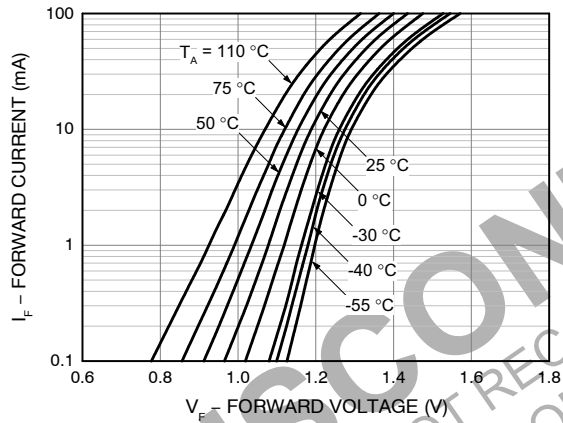


Figure 3. Forward Current vs. Forward Voltage

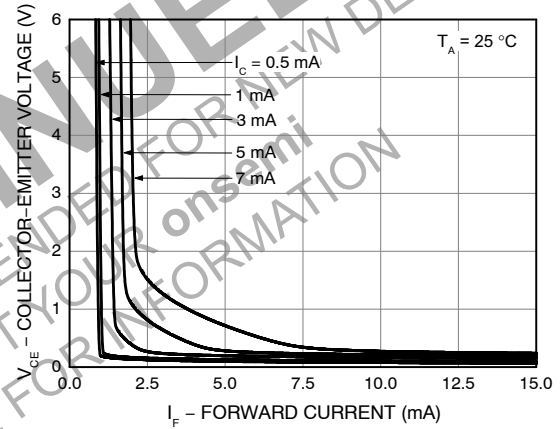


Figure 4. Collector-Emitter Voltage vs. Forward Current

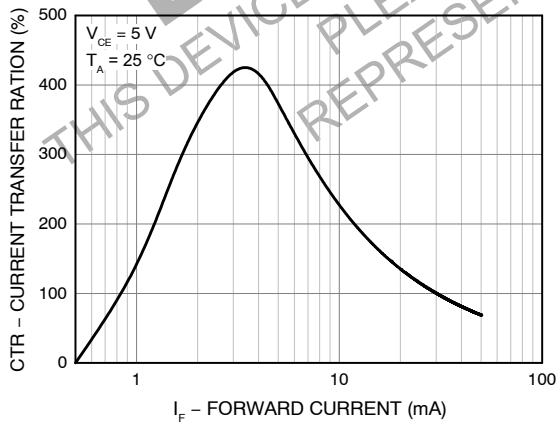


Figure 5. Current Transfer Ratio vs. Forward Current

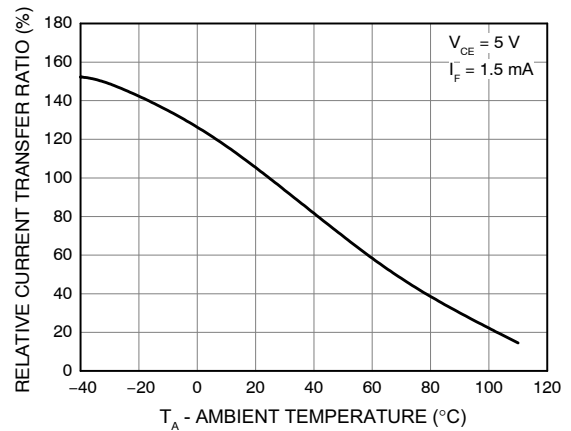


Figure 6. Relative Current Transfer Ratio vs. Ambient Temperature

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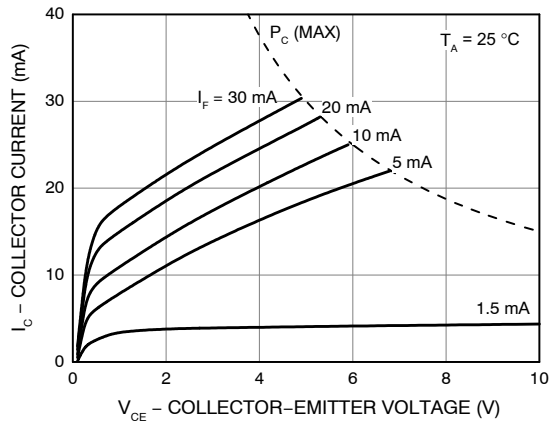


Figure 7. Collector Current vs. Collector-Emitter Voltage

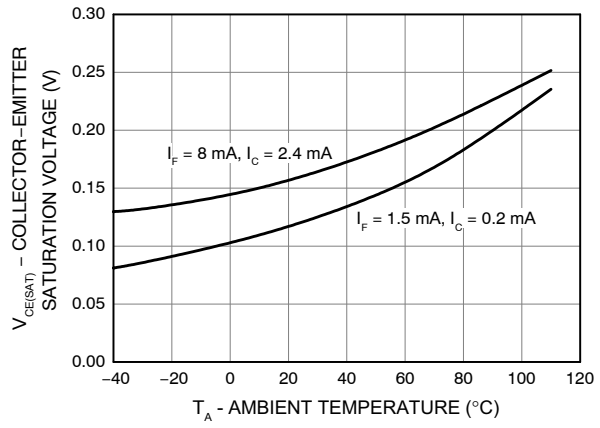


Figure 8. Collector-Emitter Saturation Voltage vs. Ambient Temperature

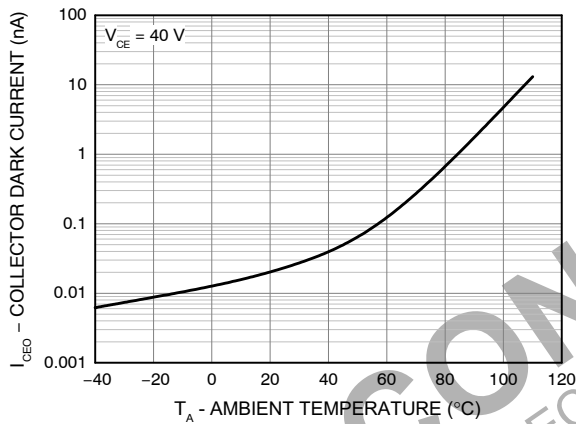


Figure 9. Collector Dark Current vs. Ambient Temperature

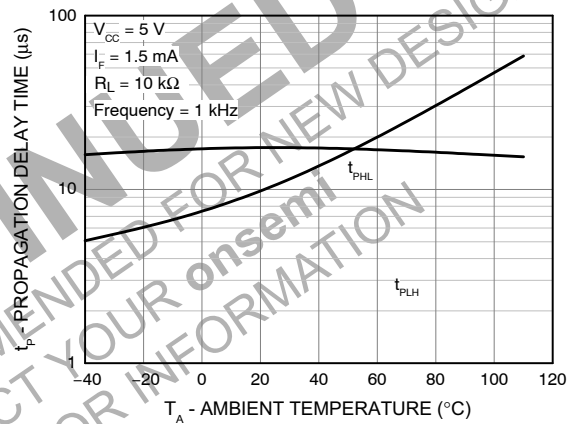


Figure 10. Propagation Delay vs. Ambient Temperature

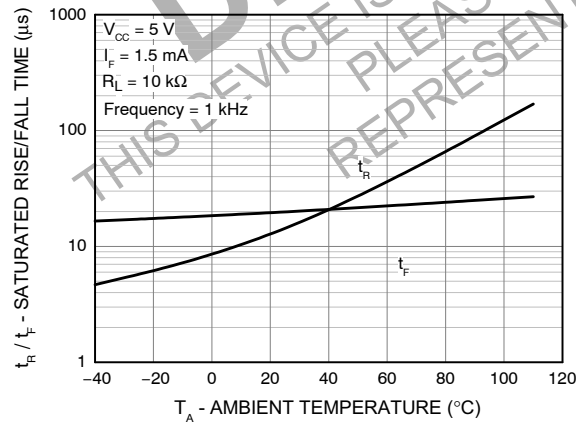


Figure 11. Saturated Rise / Fall Time vs. Ambient Temperature

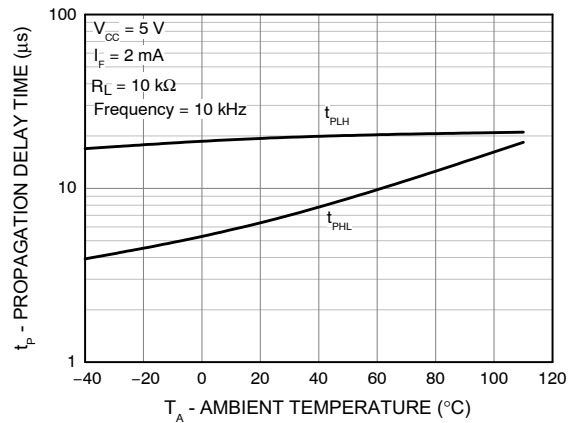


Figure 12. Propagation Delay vs. Ambient Temperature

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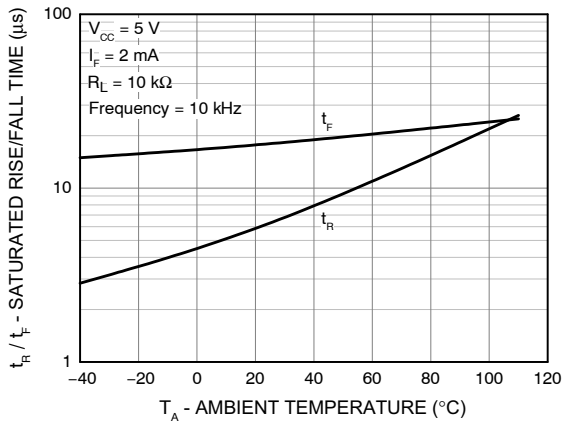


Figure 13. Collector Dark Current vs. Ambient Temperature

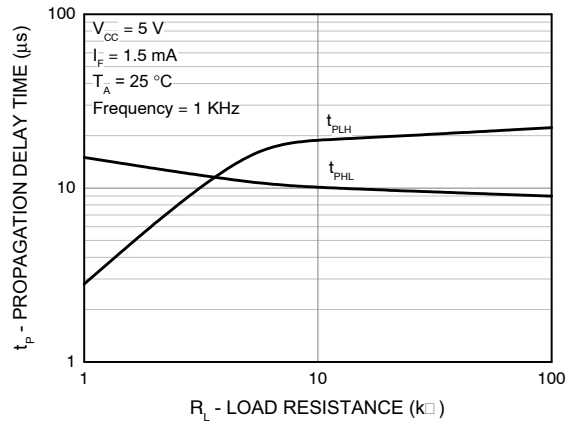


Figure 14. Propagation Delay vs. Ambient Temperature

Test Circuit

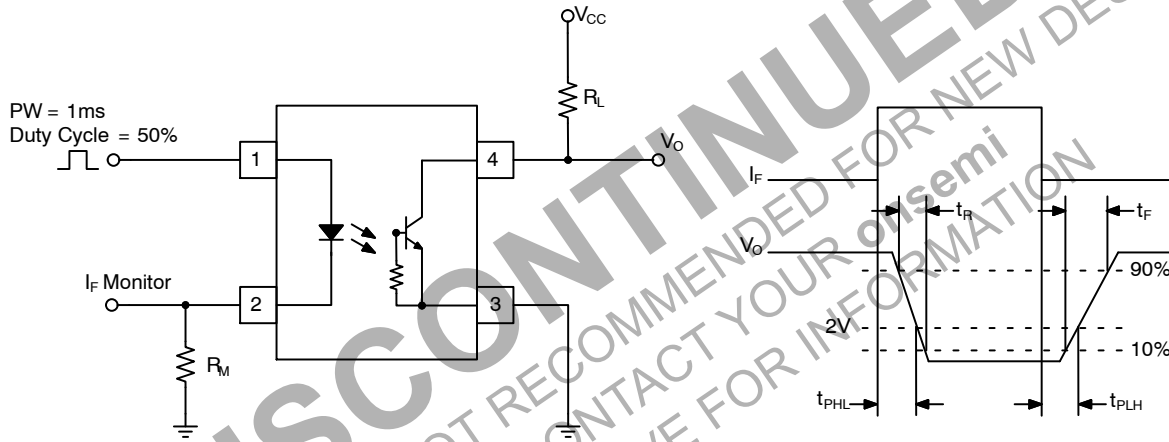


Figure 15. Test Circuit for Response Time

Figure 16. Timing Diagram

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Reflow Profile

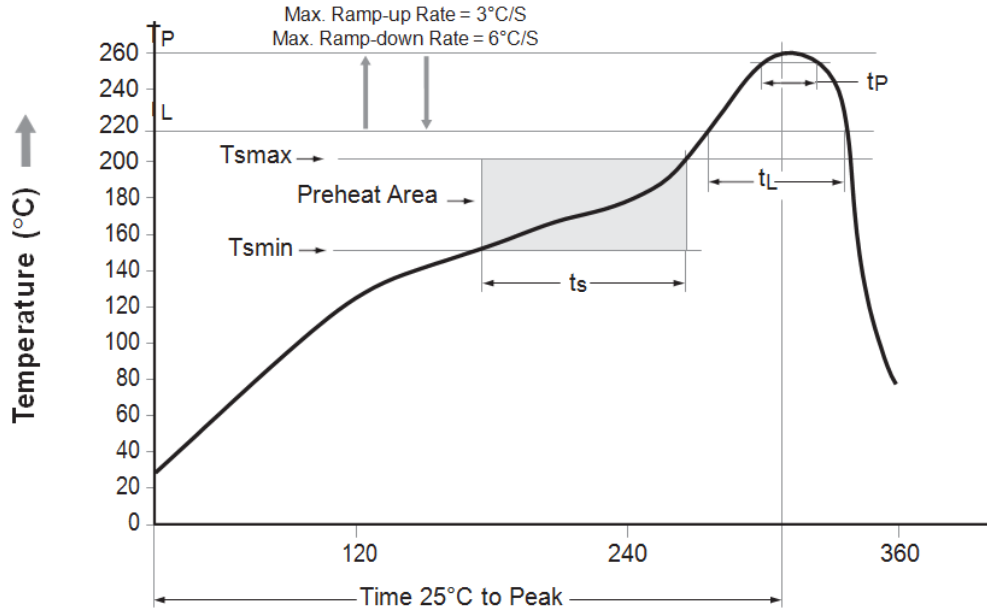


Figure 17. Reflow Profile

Table 6.

Profile Feature	Pb-Free Assembly Profile
Temperature Min. (T _{min})	150°C
Temperature Max. (T _{max})	200°C
Time (t _s) from (T _{min} to T _{max})	60–120 seconds
Ramp-up Rate (t _L to t _p)	3°C/second max.
Liquidous Temperature (T _L)	217°C
Time (t _L) Maintained Above (T _L)	60–150 seconds
Peak Body Package Temperature	260°C +0°C / -5°C
Time (t _p) within 5°C of 260°C	30 seconds
Ramp-down Rate (T _P to T _L)	6°C / second max.
Time 25°C to Peak Temperature	8 minutes max.

Table 7. ORDERING INFORMATION

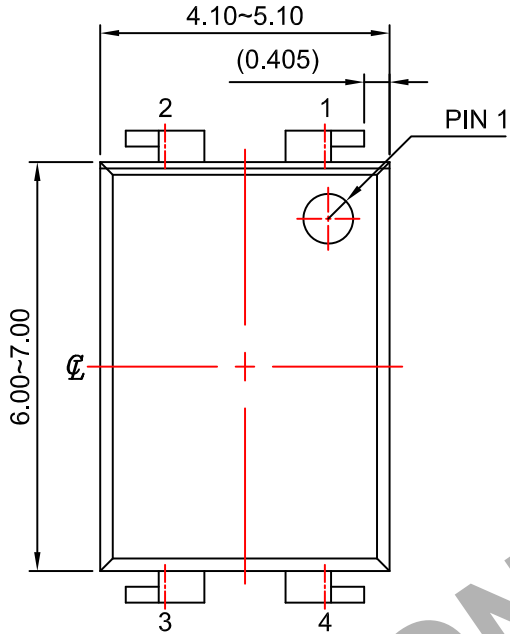
Part Number	Package	Packing Method †
FOD819	DIP 4-Pin	Tube (100 units per tube)
FOD819S	SMT 4-Pin (Lead Bend)	Tube (100 units per tube)
FOD819SD	SMT 4-Pin (Lead Bend)	Tape and Reel (1,000 units per reel)
FOD819300	DIP 4-Pin, DIN EN/IEC60747-5-5 option	Tube (100 units per tube)
FOD8193S	SMT 4-Pin (Lead Bend), DIN EN/IEC60747-5-5 option	Tube (100 units per tube)
FOD8193SD	SMT 4-Pin (Lead Bend), DIN EN/IEC60747-5-5 option	Tape and Reel (1,000 units per reel)
FOD819300W	DIP 4-Pin, 0.4" Lead Spacing, DIN EN/IEC60747-5-5 option	Tube (100 units per tube)

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

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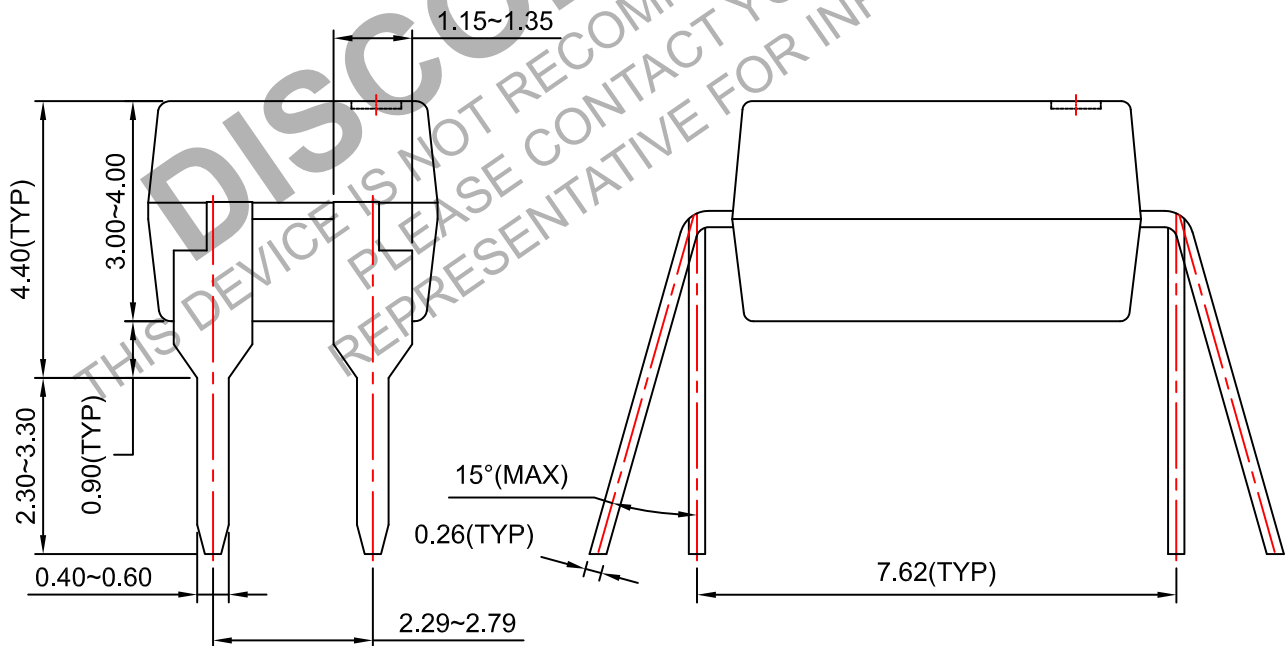
PACKAGE DIMENSIONS

PDIP4 4.6 x 6.5, 2.54P
CASE 646CD
ISSUE O



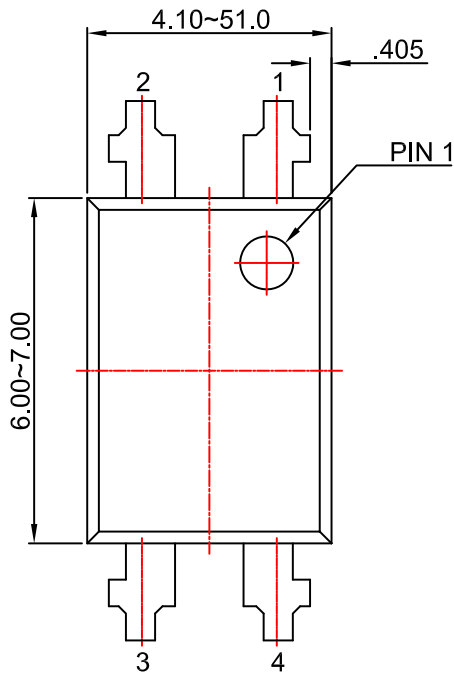
NOTES:

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- B) ALL DIMENSIONS ARE IN MILLIMETERS.
- C) DIMENSIONS ARE EXCLUSIVE OF BURRS, MOLD FLASH, AND TIE BAR EXTRUSION



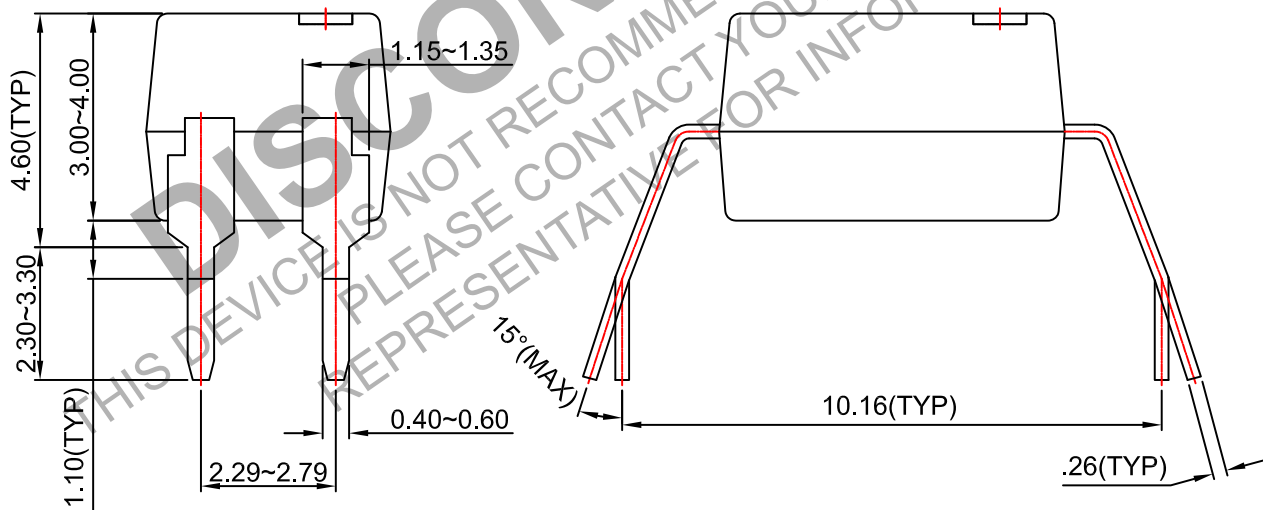
FOD819 Series

PDIP4 4.6 x 6.5, 2.54P
CASE 646CA
ISSUE O



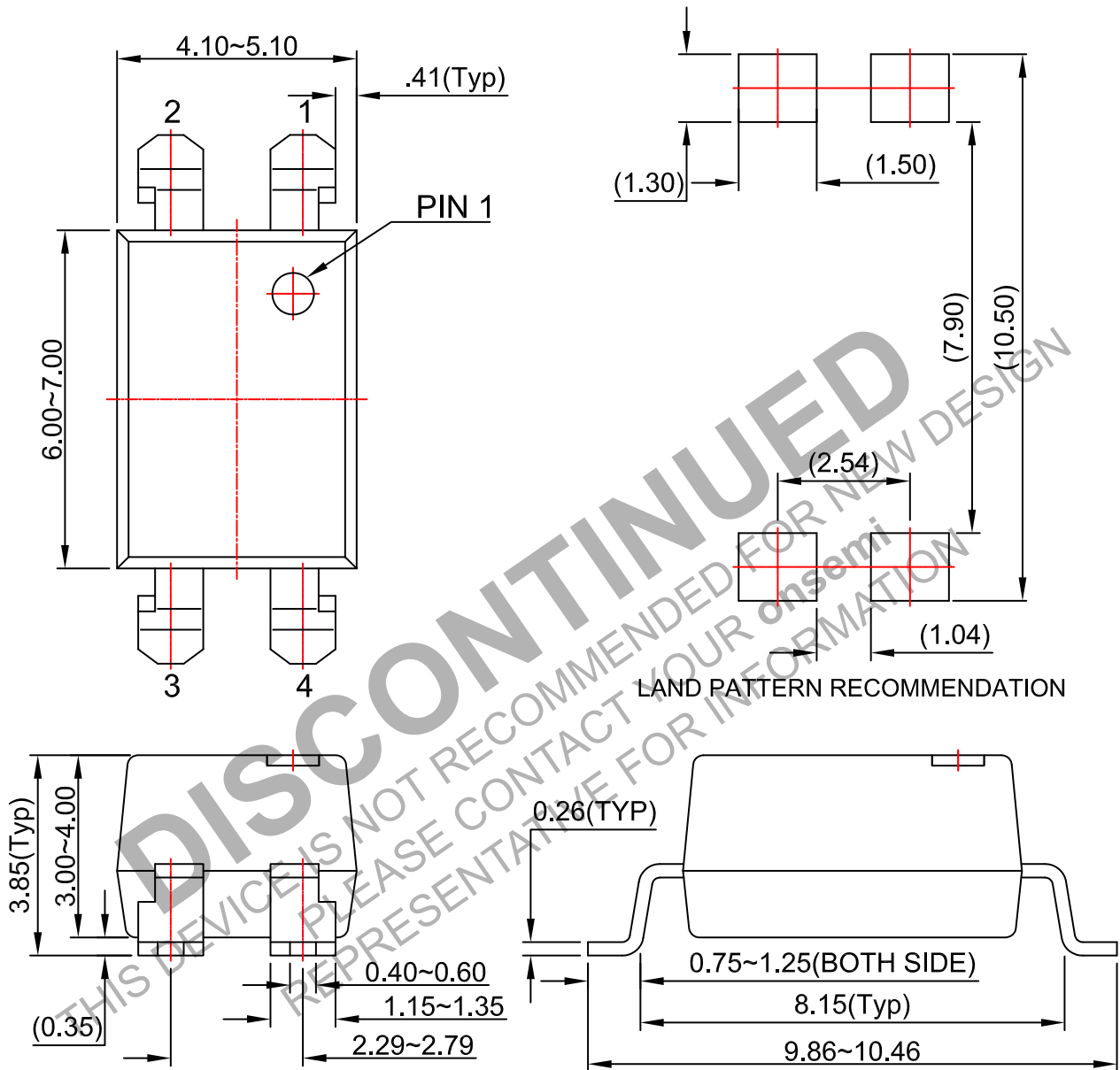
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PDIP4 GW
CASE 709AH
ISSUE A



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